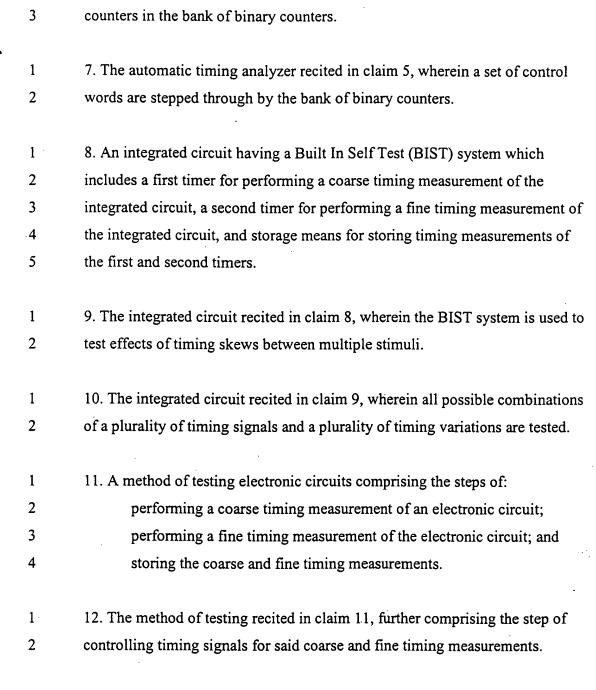
## **CLAIMS**

Having thus described our invention, what we claim as new and desire to secure by Letters Patent is as follows:

1	1. An automatic timing analyzer of testing electronic circuits comprising:
2	a first timer for performing a coarse timing measurement of an
3	electronic circuit;
4	a second timer for performing a fine timing measurement of the
5	electronic circuit; and
6	storage means for storing timing measurements of the first and second
7	timers.
1	2. The automatic timing analyzer recited in claim1, wherein the electronic
2	circuits are integrated circuits and the timing analyzer is a component of a
3	Built In Self Test (BIST) system on an integrated circuit.
1	3. The automatic timing analyzer recited in claim 2, wherein the BIST system
2	includes separately controlled delay elements for controlling timing of output
3	signals for said first and second timers.
1	4. The automatic timing analyzer recited in claim 3, wherein the delay
2	elements are controlled by individual control words.
1	5. The automatic timing analyzer recited in claim 4, wherein the control words
2	are generated from a bank of binary counters.
1	6. The automatic timing analyzer recited in claim 5, wherein relative timing of

output signals is adjusted by incrementing or decrementing respective

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13. The method of testing recited in claim 12, wherein the step of controlling

is performed using individual control words.

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- 1 14. The method of testing recited in claim 13, further comprising the step of
- 2 generating the individual control words with a bank of binary counters.
- 1 15. The method of testing recited in claim 14, further comprising the step of
- 2 incrementing or decrementing respective counters in the bank of binary
- 3 counters to adjust relative timing for said coarse and fine testing
- 4 measurements.